

APPENDIX 3: Photographs of test setup

Conducted Emission

(Camera View + USB Communication + microSD card Access Mode)



Photo 1



Photo 2

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Conducted Emission
(Charging + microSD card Access Mode)



Photo 1



Photo 2

Radiated Emission
(Camera View + USB Communication + microSD card Access Mode)
Below 1GHz



Photo 1



Photo 2

Radiated Emission
(Charging + microSD card Access Mode)
Below 1GHz



Photo 1

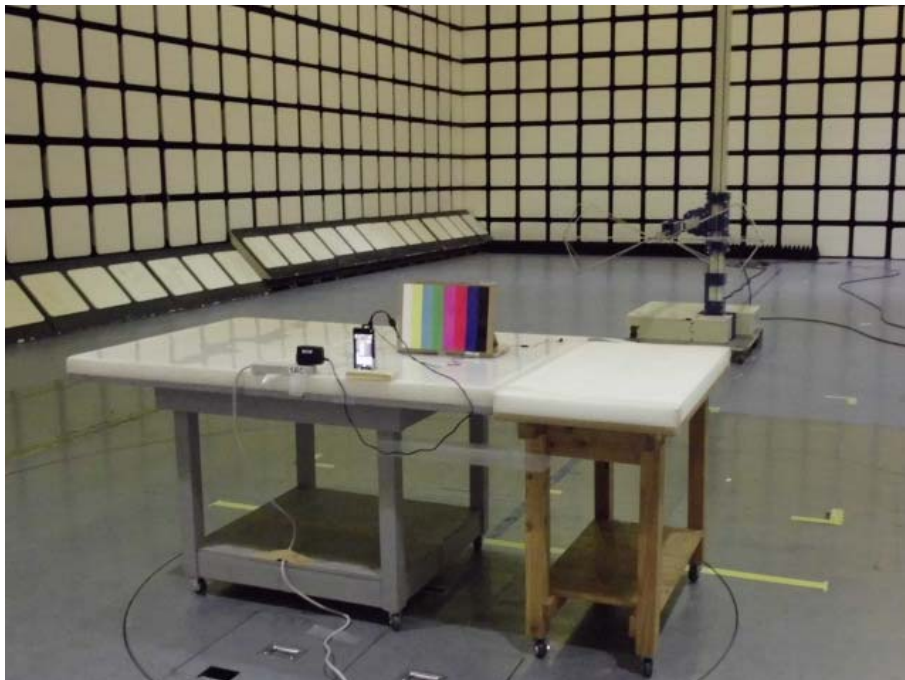


Photo 2

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Radiated Emission
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Radiated Emission
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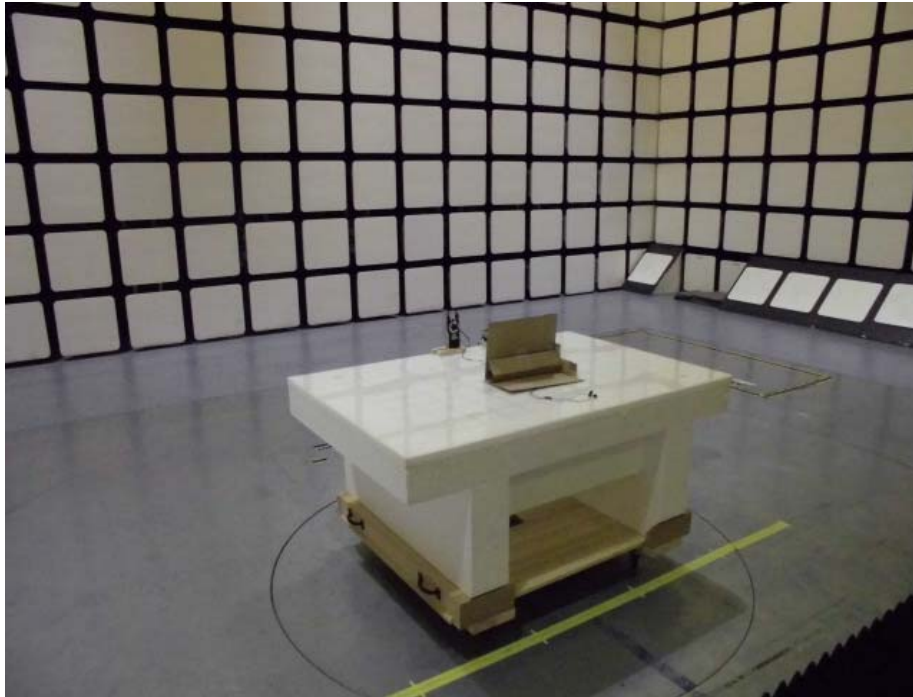


Photo 1

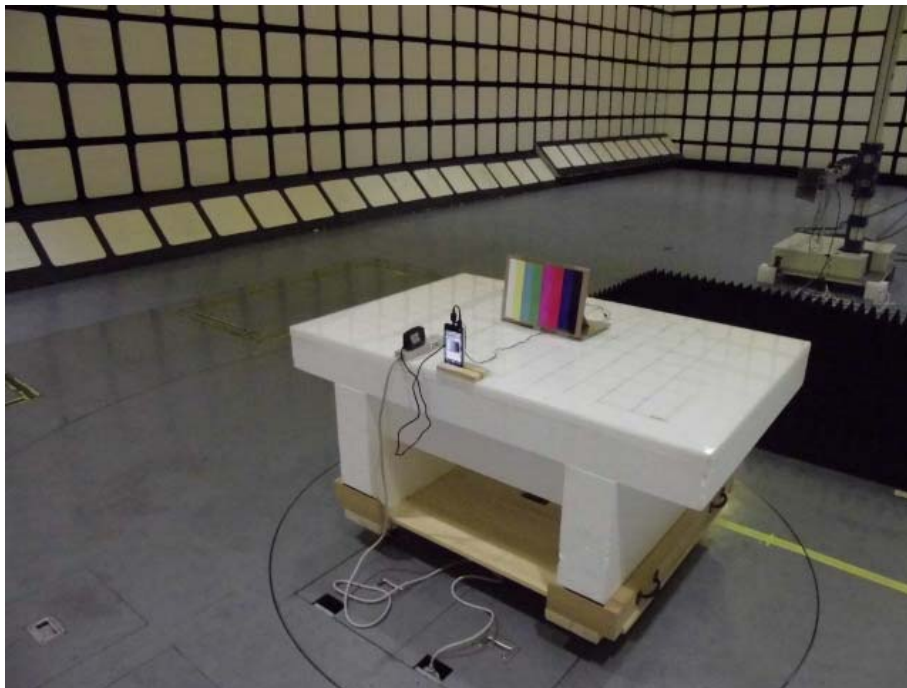


Photo 2

Worst Case Position
(Horizontal: Z-axis/ Vertical:Z-axis)

X-axis



Y-axis



Z-axis



End of Report

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